

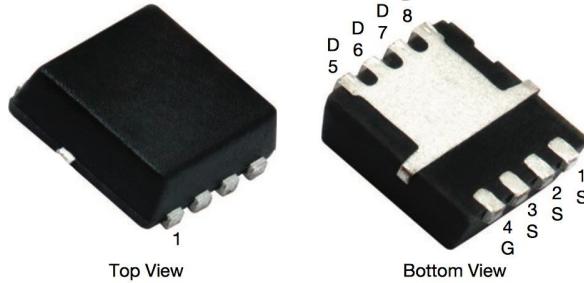
## N-Channel Enhancement Mode Power MOSFET

### Features

$V_{DS} = 100V$   
 $I_D = 47.3A$   
 $R_{DS(ON)} @ V_{GS} = 10V, TYP 9.3m\Omega$   
 $R_{DS(ON)} @ V_{GS} = 4.5V, TYP 12m\Omega$

MARKING: S1008

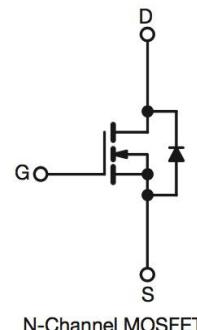
### Pin Configurations



PDFN3\*3-8L

### General Description

DC/DC conversion  
• Synchronous rectification



N-Channel MOSFET

### Absolute Maximum Ratings @ $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Ratings	Unit
Drain-Source Voltage	$V_{DS}$	100	V
Gate-Source Voltage	$V_{GSS}$	$\pm 20$	V
Drain Current (Continuous) *C	$I_D$	47.3	A
$T_C=70^\circ C$		37.8	
Drain Current (Pulse) *B	$I_{DM}$	189.2	A
Power Dissipation	$P_D$	57	W
Operating Temperature/ Storage Temperature	$T_J/T_{STG}$	-55~150	°C

### Thermal Resistance Ratings

Parameter	Symbol	Maximum	Unit
Maximum Junction-to-Ambient *A	$R_{thJA}$	30	°C/W
Maximum Junction-to-Case (Drain)	$R_{thJC}$	2.2	

**Electrical Characteristics @ $T_A=25^\circ\text{C}$  unless otherwise noted**

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
<b>Static *D</b>						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	100	--	--	V
Zero Gate Voltage Drain Current	$I_{\text{DSS}}$	$V_{\text{DS}} = 80\text{V}, V_{\text{GS}} = 0\text{V}$	--	--	1	$\mu\text{A}$
Gate Threshold Voltage	$V_{\text{GS}(\text{TH})}$	$V_{\text{GS}} = V_{\text{DS}}, I_{\text{DS}} = 250\mu\text{A}$	1	--	2.5	V
Gate Leakage Current	$I_{\text{GSS}}$	$V_{\text{GS}} = \pm 20\text{V}, V_{\text{DS}} = 0\text{V}$	--	--	$\pm 100$	nA
Drain-Source On-state Resistance	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}} = 10\text{V}, I_D = 20\text{A}$	--	9.3	12.1	$\text{m}\Omega$
	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}} = 4.5\text{V}, I_D = 10\text{A}$	--	12.0	15.6	$\text{m}\Omega$
Diode Forward Voltage	$V_{\text{SD}}$	$I_{\text{SD}} = 1\text{A}, V_{\text{GS}} = 0\text{V}$	--	--	1.2	V
Diode Forward Current *C	$I_{\text{S}}$	$T_C = 25^\circ\text{C}$	--	--	47.3	A
<b>Switching</b>						
Total Gate Charge	$Q_g$	$V_{\text{GS}} = 10\text{V}, V_{\text{DS}} = 50\text{V}, I_{\text{DS}} = 20\text{A}$	--	17.8	--	nC
Gate-Source Charge	$Q_{\text{gs}}$		--	3	--	nC
Gate-Drain Charge	$Q_{\text{gd}}$		--	3.9	--	nC
Turn-on Delay Time	$t_{\text{d}(\text{on})}$	$V_{\text{DS}} = 50\text{V}, V_{\text{GEN}} = 10\text{V}, R_G = 3\Omega, I_{\text{DS}} = 20\text{A}$	--	3.4	--	ns
Turn-on Rise Time	$t_r$		--	3.5	--	ns
Turn-off Delay Time	$t_{\text{d}(\text{off})}$		--	15	--	ns
Turn-off Fall Time	$t_f$		--	8.5	--	ns
<b>Dynamic</b>						
Input Capacitance	$C_{\text{iss}}$	$V_{\text{DS}} = 50\text{V}, V_{\text{GS}} = 0\text{V}, f = 1.0\text{MHz}$	--	1048	--	pF
Output Capacitance	$C_{\text{oss}}$		--	482	--	pF
Reverse Transfer Capacitance	$C_{\text{rss}}$		--	11	--	pF

A: The value of  $R_{\text{thJC}}$  is measured with the device mounted on 1in2 FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The value in any given application depends on the user's specific board design.

B: Repetitive rating, pulse width limited by junction temperature.

C: The current rating is based on the junction to case thermal resistance rating.

D: Pulse Test: Pulse Width  $\leq 300\mu\text{s}$ , Duty Cycle  $\leq 2\%$ .

Typical Performance Characteristics @ $T_J = 25^\circ\text{C}$ , unless otherwise noted

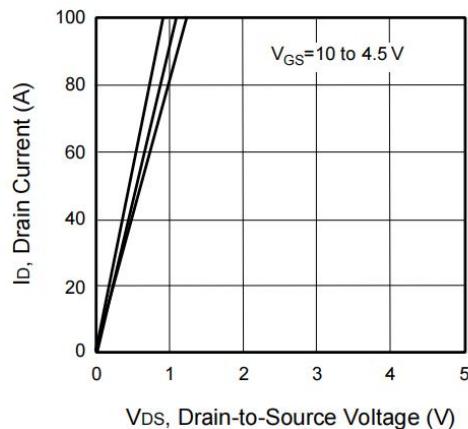


Figure 1. Output Characteristics

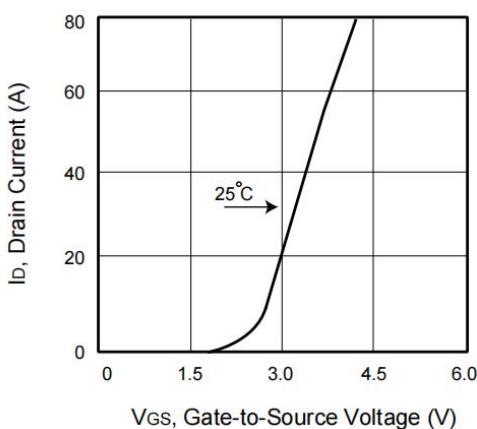


Figure 2. Transfer Characteristics

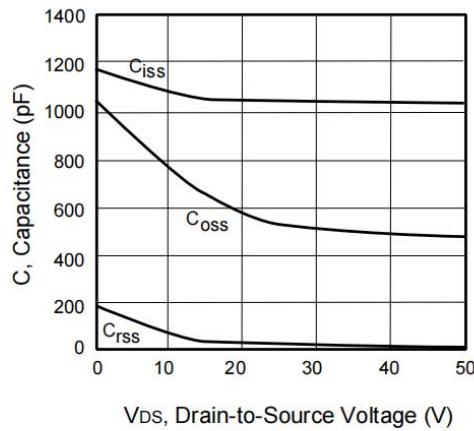


Figure 3. Capacitance

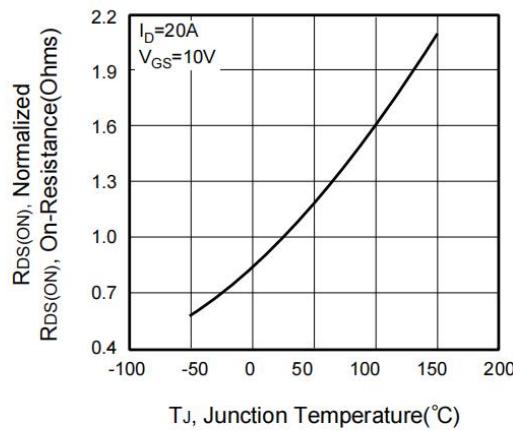


Figure 4. On-Resistance Variation with Temperature

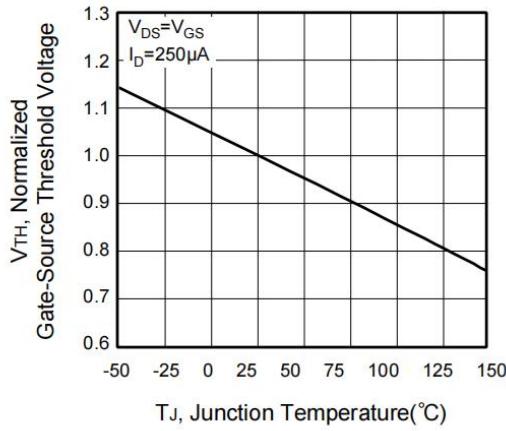


Figure 5. Gate Threshold Variation with Temperature

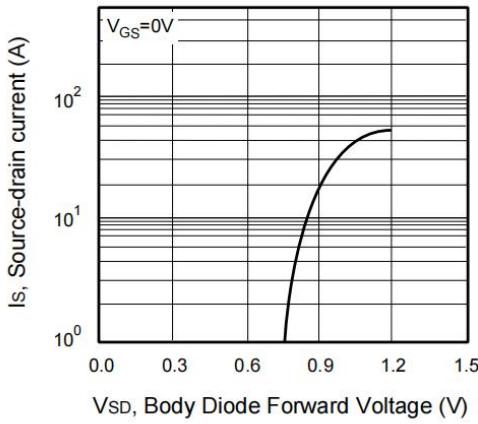


Figure 6. Body Diode Forward Voltage Variation with Source Current

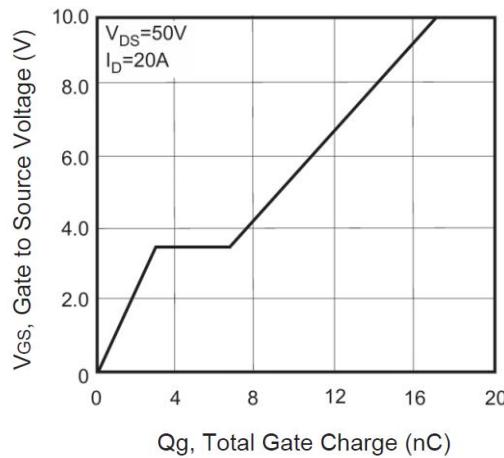


Figure 7. Gate Charge

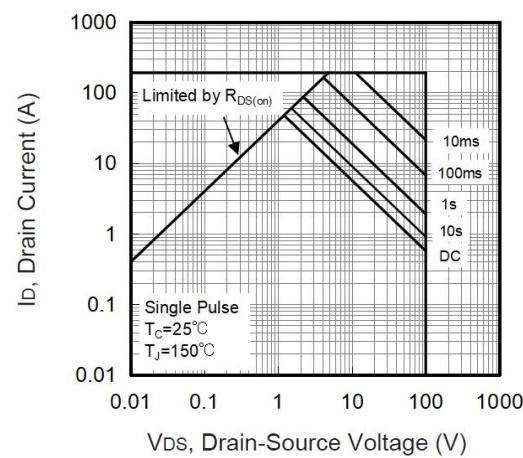


Figure 8. Maximum Safe Operating Area

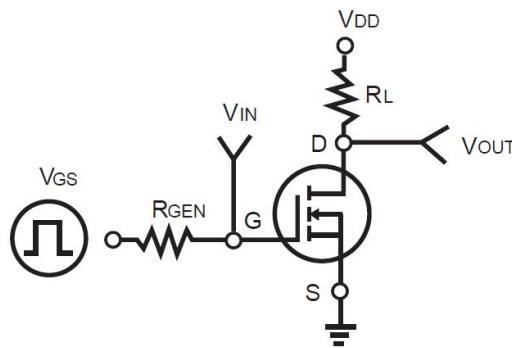


Figure 9. Switching Test Circuit

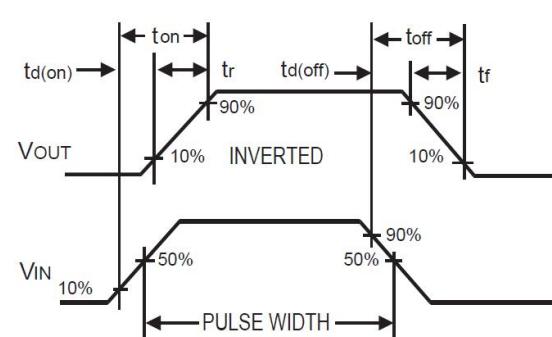


Figure 10. Switching Waveforms

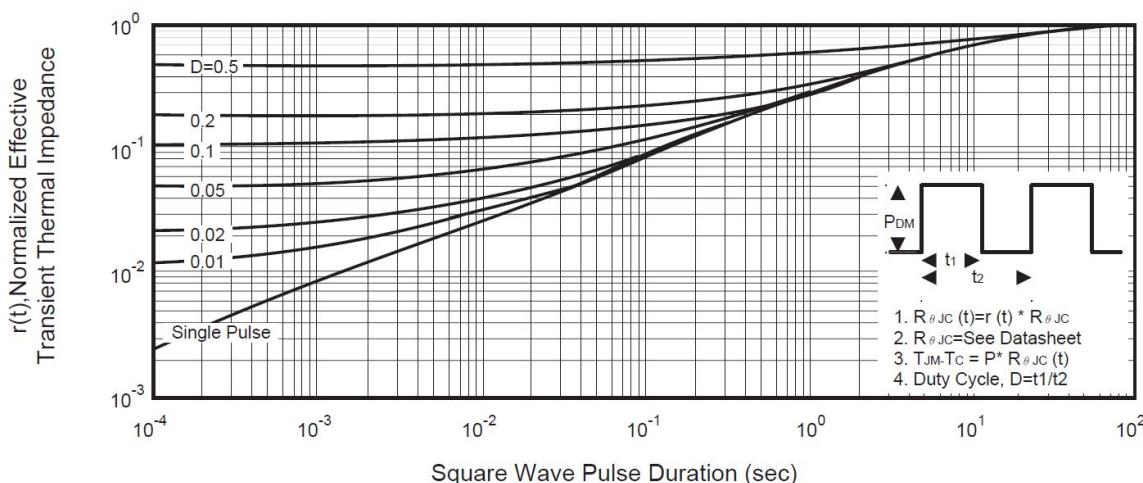


Figure 11. Normalized Thermal Transient Impedance Curve

### Package Information

